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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPLICATION NO.		CLASS		SUBCLASS		GAU		EXAMINER	
APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU					
10000089	12/04/2001	714 324	2122	2133 3050					
**APPLICANTS: Hiraide Takahisa; Yamanaka Hitoshi; Kumagai Junko; Konishi Hideoaki; Moriyama Daisuke; 2133 TRIMMINGS									
**CONTINUING DATA VERIFIED:									
** FOREIGN APPLICATIONS VERIFIED: JAPAN 2000-372231 12/07/2000 JAPAN 2001-205179 07/05/2001									
PG-PUB		DO NOT PUBLISH <input type="checkbox"/>			RESCIND <input type="checkbox"/>				
Foreign priority claimed		<input type="checkbox"/> yes <input type="checkbox"/> no			ATTORNEY DOCKET NO				
35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no			1075.1335				
Verified and Acknowledged Examiners's initials									
TITLE : Testing apparatus and testing method for an integrated circuit, and integrated circuit									
U.S. DEPT. OF COMMERCE/PAT. & TRADEMARK OFFICE (Rev. 12-94)									

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NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	
		Print Claim for O.G.	
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
		PREPARED FOR ISSUE	
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